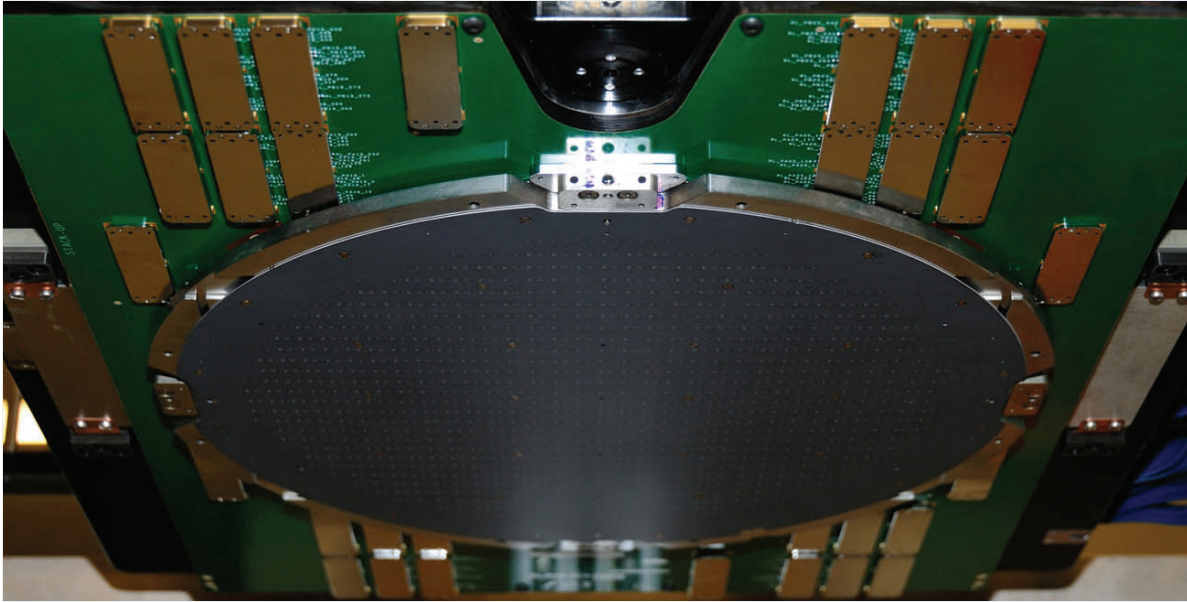


## Full Wafer Contactor

### Single Touchdown 300 mm Full-Wafer Contactor



#### CONTACTOR BENEFITS

- **High Capability**
  - ♦ Pitch as narrow as 86 micron
  - ♦ Pad size as small as 50 x 60 microns
  - ♦ Over 50,000 contacts per wafer
  - ♦ Parallel test over 4,000 flash die per wafer
- **Highly Flexible**
  - ♦ Pad Metallurgy: Al, Cu, Au or solder balls
  - ♦ Temperature range  $-40^{\circ}\text{C}$  to  $180^{\circ}\text{C}$
  - ♦ Up to 500mA per contact
  - ♦ Field repairable contactor

“Changing the Way ICs Are Tested”

#### CORPORATE HEADQUARTERS

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